Improved measurement of Te and Zeff on NSTX-U using Integrated Data Analysis **NSTX-U** L.M. Reusch¹, D.J. Den Hartog, Ahmed Diallo²

Overview

- We have begun to develop IDA to improve the precision and temporal resolution of electron temperature (Te) profiles and increase the reliability of effective ionic charge (Zeff) measurements on NSTX-Upgrade, using Integrated Data Analysis (IDA).
- Bayesian probability theory provides a natural framework for IDA, and will be applied to this project.
- We will combine data from the multi-energy soft x-ray (ME-SXR) diagnostic and charge exchange recombination spectroscopy measurements to improve Zeff estimation.
 - Zeff governs many plasma dynamics, so a more precise determination will aid validation
 - This will help enable measurements of Zeff once metal tiles are install in NSTX-U
- We will combine ME-SXR and Thomson scattering data (and others as appropriate and available) to improve Te measurement.
 - Improved precision will allow better transport and confinement studies.
 - Improved spatial and temporal resolution will aid in pedestal evolution studies.

IDA

- As we transition to fusion experiments that are full nuclear environments severe limitations will be imposed on diagnostics
- Integrated Data Analysis (IDA) provides a framework to maximum the scientific information extracted from available data
- The goal of IDA is to
 - combine data from heterogeneous and complementary diagnostics
 - consider all dependencies within and between diagnostics
 - obtain the most reliable results in a transparent and standardized way.

• IDA

- Typically results in improved precision/resolution [1].
- Enables "meta-diagnostics," information from various instruments combined to produce unique measurements [2].



Diagnostics

Charge Exchange Recombination Spectroscopy (CHERS)



R. E. Bell, "Carbon ion plume emission produced by charge exchange with neutral beams on National Spherical Torus Experiment." Rev. Sci. Instrum. 77, 10E902 (2006).

R. E. Bell and R. Feder, "Measurement of poloidal velocity on the National Spherical Torus Experiment (invited)." Rev. Sci. Instrum. 81, 10D724 (2010).

Multi-energy soft x-ray diagnostic (ME-SXR)



K. Tritz, D. J. Clayton, D. Stutman, and M. Finkenthal, "Compact diode-based multi- energy soft x-ray diagnostic for NSTX," Rev. Sci. Instrum. 83, 10E109 (2012).

Thomson Scattering (TS)



A. Diallo, B. P. LeBlanc, G. Labik, and D. Stevens, "Prospects for the Thomson scattering system on NSTX-Upgrade." Rev. Sci. Instrum. 83, 10D532 (2012).

B. P. LeBlanc A. Diallo, G. Labik, and D. R. Stevens, "Radial resolution enhancement of the NSTX Thomson scattering diagnostic." Rev. Sci. Instrum. 83, 10D527 (2012).





Bayesian Probability Theory • Bayesian analysis relies on Bayes' Rule:

 $P(x|y, I) \propto P(x|y, I)P(x|I)$

- where x and y are different (conditional) events, and I is the background information
- read as "the probability of x given y and I is proportional to the probably of y given x and I"
- and marginalization:

$$\mathbf{P}(x|y,I) = \int \mathbf{P}(x,\alpha|y,I)d\alpha$$

- here x, y, and α are parameters and I is the background information

- allows for the removal of nuisance parameters through integration over all possible values for α .

Bayesian Analysis of Data

- Bayesian analysis of a single diagnostic data takes the form:
 - Z_{eff} : $P(Z_{\text{eff}}|D,I) \propto P(D|Z_{\text{eff}},I)P(Z_{\text{eff}}|I)$
 - $-T_e: P(T_e|D, I) \propto P(D|T_e, I)P(T_e|I)$
 - -D is the diagnostic data from an individual diagnostic.
 - $P(Z_{eff}|D, I)$, the posterior probability, is the answer: an estimate of Z_{eff} given the diagnostic data.
 - $P(D|Z_{eff}, I)$, the likelihood function, relates the diagnostic data to Z_{eff} through a diagnostic forward model

- The forward model of the system includes all physical processes generating signal and instrumentation effects.

- $P(Z_{eff}|I)$ represents our prior knowledge about possible values for $Z_{\rm eff}$, such as expected ranges or physical constraints.
- Bayesian analysis of multiple diagnostics takes the form:
 - $-Z_{\text{eff}}$: $P(Z_{\text{eff}}|D_1, D_2, \dots, I) \propto P(Z_{\text{eff}}|I) \times \prod_i P(D_i|Z_{\text{eff}}, I)$
 - $-T_e: P(T_e|D_1, D_2, \ldots, I) \propto P(T_e|I) \times \prod_i P(D_i|T_e, I)$
 - where D_i is the diagnostic data from an individual diagnostic and $P(D_i|T_e, I)$ is the likelihood function for each diagnostic.
 - $P(Z_{eff}|D_1, D_2, \ldots, I)$ gives the single best estimate for Z_{eff} given all the diagnostic data
 - This is how IDA is accomplished using Bayesian analysis.

SXR Forward Model

Total x-ray power come from multiple sources:

• Bremsstrahlung radiation:



• Recombination radiation:

 $P_r dE = A \sum_i \frac{n_e n_i Z_i^2}{\sqrt{T_e}} e^{-\frac{E}{T_e}}$

- Atomic Line radiation:



Filter	USXR Signal
5 μm Be	3575 W/m ²
100 µm Be	375 W/m ²

